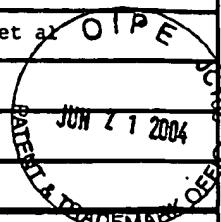


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Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application Number	10/650,059
		Filing Date	August 27, 2003
		First Named Inventor	Ryouichi YOKOYAMA et al
		Group Art Unit	2855
		Examiner Name	
Sheet	1	of	1
		Attorney Docket Number	03506/LH



OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS

Examiner Initials ¹	Cite No. ²	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published	T ³
O P E CM	1	K. TANAKA, K. ISHIHARA and K. INOUE: "A METHOD OF X-RAY STRESS MANAGEMENT FOR CUBIC POLYCRYSTALS WITH FIBER TEXTURE", J. Soc. Mat. Sci., Japan, Vol. 45, No. 8, pages 945-950, August, 1996.	
JUN 1 2004 PATENT OFFICE RECEIVED JUN 1 2004 PATENT OFFICE RECEIVED	3	K. TANAKA, Y. AKINIWA, T. ITO and K. INOUE: "ELASTIC CONSTANTS AND X-RAY STRESS MEASUREMENT OF CUBIC THIN FILMS WITH FIBER TEXTURE", JSME International Journal, Series A, Vol. 42, No. 2, pages 224-234, 1998.	
CM	4	K. TANAKA and Y. AKINIWA: "X-RAY STRESS MANAGEMENT OF HEXAGONAL POLYCRYSTALS WITH [001] FIBER TEXTURE", JSME International Journal, Series A, Vol. 41, No. 2, pages 287-289, 1998.	
CH	5	Jikkenbutsurigaku kouza 20, X-sen kaisetsu (Experimental physics course 20, x-ray diffraction), edited by K. Kohra, KYORITSU SHUPPAN CO., LTD., 1998, pages 571-575, "16.2 x-sen ouryokusokuteino genri (Principle of X-ray stress measurement)".	
X-sen kesshoukaisekino tebiki, Ouyoubutsurigaku sensho (Guide to X-ray Crystal Analysis, Applied Physics Sampler), T. Sakurai, Shokabou, 1983, page 53.			

Examiner Signature

Date Considered

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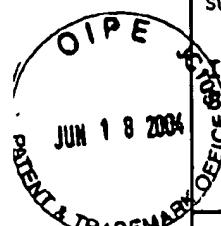
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				Filing Date August 27, 2003
				First Named Inventor Ryouichi YOKOYAMA et al
				Group Art Unit 2855
				Examiner Name
Sheet	1	of	2	Attorney Docket Number 03506/LH

OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
CM	2	Tanaka et al., "X-ray residual stress measurement of aluminum thin films with 111 fiber texture" Journal of the Society of Materials Science, Japan, Soc. Mater. Sci. Japan, Japan, Vol. 45, No. 10, pages 1138-1144, XP00902646, ISSN: 0514-5163, October 1996.	
CM	3	Lappalainen J. Et al., "Electrical and Mechanical Properties of Ferroelectric Thin Films Laser Ablated from a PBO.97NDO.02 (ZRO.55TIO.45)03 Target" Journal of Applied Physics, American Institute of Physics. New York, US, Vol. 82, No. 7, pages 3469-3477, XP000738070, ISSN: 0021-8979, October 1, 1997.	

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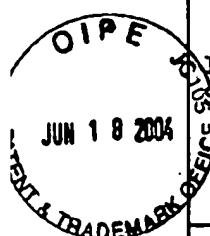
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Sheet	1	of 2	Attorney Docket Number 03506/LH

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